

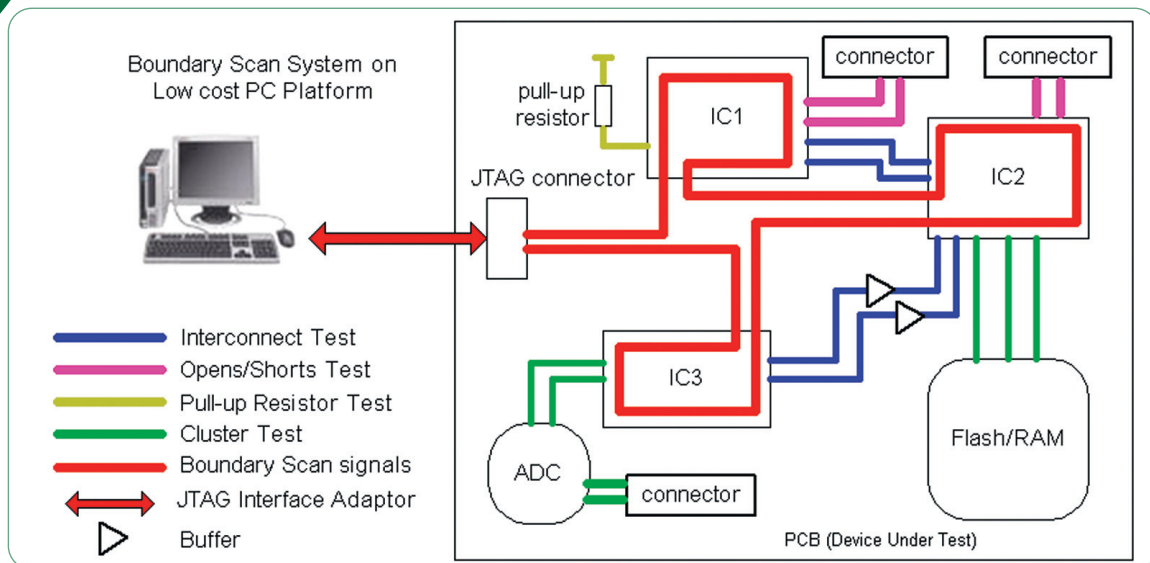
IEEE 1149.1 Boundary Scan Testing

IEEE 1149.1 Boundary Scan or widely known as JTAG is a methodology allowing complete controllability and monitoring of the boundary pins of a JTAG compatible device via software control.

Why Boundary Scan?

The industrial move to surface mount technology and multilayer boards has made testing via bed of nails system limited and inefficient. Boundary Scan test provides high test coverage for digital Printed Circuit Board and has the following advantages:

- ✓ *Overcome the constraint on the limited access of high density boards**
- ✓ *Virtual access to the board.*
- ✓ *Cost savings from not requiring fixtures in some cases.*
- ✓ *Operates on low cost PC platform.*
- ✓ *Precise fault diagnosis during manufacturing*
- ✓ *Easy integration with functional test.*
- ✓ *Automated testing controlled by Test Executive.*



Boundary Scan Test Coverage

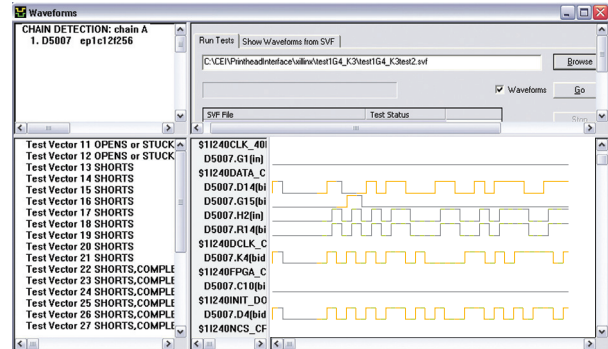
- ✓ *ID code verification of devices.*
- ✓ *Flash Programming.*
- ✓ *Interconnect test between Boundary Scan IC chips.*
- ✓ *Open and Short-circuit test of PCB connectors.*
- ✓ *Pull-up resistor test.*
- ✓ *Perform cluster test on Non-Boundary Scan enabled devices. eg. Flash, SRAM, EPROMS, ADC, I2C devices etc.*

IEEE 1149.1 Boundary Scan Testing

IEEE 1149.1 Boundary Scan or widely known as JTAG is a methodology allowing complete controllability and monitoring of the boundary pins of a JTAG compatible device via software control.

Evaluation Services

Our company provides boundary scan testability assessment for your product and customize to your testing requirements. SysEng also provide evaluation services with boundary scan development tools to verify your board design.



Customization

Customized off-line or in-line jig fixtures depending on customers testing requirements.



In-line Jig Fixture



Off-line Jig Fixture



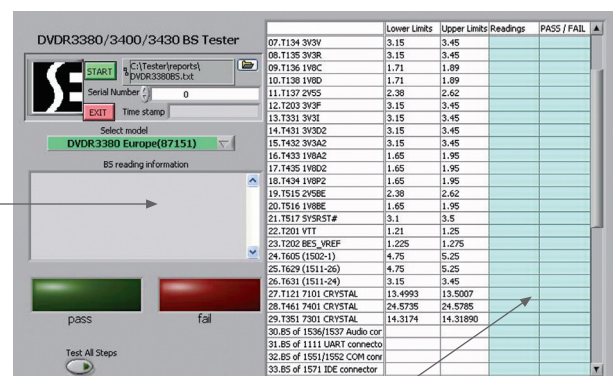
JTAG Interface Adaptor

Precise Diagnosis

Diagnosis Message:

Net /VCR_DA_OUT: check for open between driver pin 7101.Y16 and pin 7101.W18.

- ✓ Easy to operate User Interface and customized report generation.
- ✓ Precise Diagnosis Window that pinpoint faults to pin level of IC chip that allows repairing of fault quicker than conventional way of testing.



Test Step	Lower Limits	Upper Limits/Readings	PASS / FAIL
07.7134 3V3V	3.15	3.45	
08.7135 3V3R	3.15	3.45	
09.7136 1V8C	1.71	1.89	
10.7138 1V8D	1.71	1.89	
11.7137 2V5S	2.38	2.62	
12.7203 3V3P	3.15	3.45	
13.7331 3V3I	3.15	3.45	
14.7431 3V3O2	3.15	3.45	
15.7432 3V3A2	3.15	3.45	
16.7433 1V8A2	1.65	1.95	
17.7435 1V8D2	1.65	1.95	
18.7434 1V8P2	1.65	1.95	
19.7515 2V5B	2.38	2.62	
20.7516 1V8B	1.65	1.95	
21.7517 SVSRST#	3.1	3.5	
22.7201 VIT	1.21	1.25	
23.7202 BES_VREF	1.225	1.275	
24.7605 (1502-1)	4.75	5.25	
25.7629 (1511-20)	4.75	5.25	
26.7631 (1511-24)	3.15	3.45	
27.7121 7101 CRYSTAL	13.4993	13.5007	
28.7461 7401 CRYSTAL	24.5738	24.5785	
29.7351 7301 CRYSTAL	14.3174	14.31890	
30.85 of 1536/1552 Audio con			
31.85 of 1111 UART connector			
32.85 of 1551/1552 COM con			
33.85 of 1571 IDE connector			

Indicates PASS/FAIL status and measured values of each test step.